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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	120MHz
Connectivity	CANbus, Ethernet, I ² C, IrDA, LINbus, Memory Card, SPI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, I ² S, LCD, POR, PWM, WDT
Number of I/O	82
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	132K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 16x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-LQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f217vet6

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3 Functional overview

3.1 ARM[®] Cortex[®]-M3 core with embedded Flash and SRAM

The ARM[®] Cortex[®]-M3 processor is the latest generation of ARM processors for embedded systems. It was developed to provide a low-cost platform that meets the needs of MCU implementation, with a reduced pin count and low-power consumption, while delivering outstanding computational performance and an advanced response to interrupts.

The ARM[®] Cortex[®]-M3 32-bit RISC processor features exceptional code-efficiency, delivering the high-performance expected from an ARM core in the memory size usually associated with 8- and 16-bit devices.

With its embedded ARM[®] core, the STM32F21x family is compatible with all ARM[®] tools and software.

Figure 4 shows the general block diagram of the STM32F21x family.

3.2 Adaptive real-time memory accelerator (ART Accelerator™)

The ART Accelerator™ is a memory accelerator which is optimized for STM32 industry-standard ARM[®] Cortex[®]-M3 processors. It balances the inherent performance advantage of the ARM[®] Cortex[®]-M3 over Flash memory technologies, which normally requires the processor to wait for the Flash memory at higher operating frequencies.

To release the processor full 150 DMIPS performance at this frequency, the accelerator implements an instruction prefetch queue and branch cache which increases program execution speed from the 128-bit Flash memory. Based on CoreMark[®] benchmark, the performance achieved thanks to the ART accelerator is equivalent to 0 wait state program execution from Flash memory at a CPU frequency up to 120 MHz.

3.3 Memory protection unit

The memory protection unit (MPU) is used to manage the CPU accesses to memory to prevent one task to accidentally corrupt the memory or resources used by any other active task. This memory area is organized into up to 8 protected areas that can in turn be divided up into 8 subareas. The protection area sizes are between 32 bytes and the whole 4 gigabytes of addressable memory.

The MPU is especially helpful for applications where some critical or certified code has to be protected against the misbehavior of other tasks. It is usually managed by an RTOS (real-time operating system). If a program accesses a memory location that is prohibited by the MPU, the RTOS can detect it and take action. In an RTOS environment, the kernel can dynamically update the MPU area setting, based on the process to be executed.

The MPU is optional and can be bypassed for applications that do not need it.

Table 7. STM32F21x pin and ball definitions (continued)

Pins					Pin name (function after reset) ⁽¹⁾	Pin type	I / O structure	Note	Alternate functions	Additional functions
LQFP64	LQFP100	LQFP144	LQFP176	UFBGA176						
-	57	79	98	N15	PD10	I/O	FT	-	FSMC_D15, USART3_CK, EVENTOUT	-
-	58	80	99	N14	PD11	I/O	FT	-	FSMC_A16, USART3_CTS, EVENTOUT	-
-	59	81	100	N13	PD12	I/O	FT	-	FSMC_A17, TIM4_CH1, USART3_RTS, EVENTOUT	-
-	60	82	101	M15	PD13	I/O	FT	-	FSMC_A18, TIM4_CH2, EVENTOUT	-
-	-	83	102	-	V _{SS}	S		-	-	-
-	-	84	103	J13	V _{DD}	S		-	-	-
-	61	85	104	M14	PD14	I/O	FT	-	FSMC_D0, TIM4_CH3, EVENTOUT	-
-	62	86	105	L14	PD15	I/O	FT	-	FSMC_D1, TIM4_CH4, EVENTOUT	-
-	-	87	106	L15	PG2	I/O	FT	-	FSMC_A12, EVENTOUT	-
-	-	88	107	K15	PG3	I/O	FT	-	FSMC_A13, EVENTOUT	-
-	-	89	108	K14	PG4	I/O	FT	-	FSMC_A14, EVENTOUT	-
-	-	90	109	K13	PG5	I/O	FT	-	FSMC_A15, EVENTOUT	-
-	-	91	110	J15	PG6	I/O	FT	-	FSMC_INT2, EVENTOUT	-
-	-	92	111	J14	PG7	I/O	FT	-	FSMC_INT3, USART6_CK, EVENTOUT	-
-	-	93	112	H14	PG8	I/O	FT	-	USART6_RTS, ETH_PPS_OUT, EVENTOUT	-
-	-	94	113	G12	V _{SS}	S	-	-	-	-
-	-	95	114	H13	V _{DD}	S	-	-	-	-
37	63	96	115	H15	PC6	I/O	FT	-	I2S2_MCK, TIM8_CH1, SDIO_D6, USART6_TX, DCMI_D0, TIM3_CH1, EVENTOUT	-

Table 7. STM32F21x pin and ball definitions (continued)

Pins					Pin name (function after reset) ⁽¹⁾	Pin type	I / O structure	Note	Alternate functions	Additional functions
LQFP64	LQFP100	LQFP144	LQFP176	UFBGA176						
-	-	-	130	D13	PH15	I/O	FT	-	TIM8_CH3N, DCMI_D11, EVENTOUT	-
-	-	-	131	E14	PI0	I/O	FT	-	TIM5_CH4, SPI2_NSS, I2S2_WS, DCMI_D13, EVENTOUT	-
-	-	-	132	D14	PI1	I/O	FT	-	SPI2_SCK, I2S2_SCK, DCMI_D8, EVENTOUT	-
-	-	-	133	C14	PI2	I/O	FT	-	TIM8_CH4, SPI2_MISO, DCMI_D9, EVENTOUT	-
-	-	-	134	C13	PI3	I/O	FT	-	TIM8_ETR, SPI2_MOSI, I2S2_SD, DCMI_D10, EVENTOUT	-
-	-	-	135	D9	V _{SS}	S	-	-	-	-
-	-	-	136	C9	V _{DD}	S	-	-	-	-
49	76	109	137	A14	PA14 (JTCK-SWCLK)	I/O	FT	-	JTCK-SWCLK, EVENTOUT	-
50	77	110	138	A13	PA15 (JTDI)	I/O	FT	-	JTDI, SPI3_NSS, I2S3_WS, TIM2_CH1_ETR, SPI1_NSS/ EVENTOUT	-
51	78	111	139	B14	PC10	I/O	FT	-	SPI3_SCK, I2S3_SCK, UART4_TX, SDIO_D2, DCMI_D8, USART3_TX, EVENTOUT	-
52	79	112	140	B13	PC11	I/O	FT	-	UART4_RX, SPI3_MISO, SDIO_D3, DCMI_D4, USART3_RX, EVENTOUT	-
53	80	113	141	A12	PC12	I/O	FT	-	UART5_TX, SDIO_CK, DCMI_D9, SPI3_MOSI, I2S3_SD, USART3_CK, EVENTOUT	-
-	81	114	142	B12	PD0	I/O	FT	-	FSMC_D2, CAN1_RX, EVENTOUT	-
-	82	115	143	C12	PD1	I/O	FT	-	FSMC_D3, CAN1_TX, EVENTOUT	-



Table 9. Alternate function mapping (continued)

Port		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF014	AF15
		SYS	TIM1/2	TIM3/4/5	TIM8/9/10/11	I2C1/I2C2/I2C3	SPI1/SPI2/I2S2	SPI3/I2S3	USART1/2/3	UART4/5/ USART6	CAN1/CAN2/ TIM12/13/14	OTG_FS/ OTG_HS	ETH	FSMC/SDIO/ OTG_HS	DCMI		
Port C	PC0	-	-	-	-	-	-	-	-	-	-	OTG_HS_ULPI_ STP	-	-	-	-	EVENTOUT
	PC1	-	-	-	-	-	-	-	-	-	-	-	ETH_MDC	-	-	-	EVENTOUT
	PC2	-	-	-	-	-	SPI2_MISO	-	-	-	-	OTG_HS_ULPI_ DIR	ETH_MII_TXD2	-	-	-	EVENTOUT
	PC3	-	-	-	-	-	SPI2_MOSI	-	-	-	-	OTG_HS_ULPI_ NXT	ETH_MII_TX_CLK	-	-	-	EVENTOUT
	PC4	-	-	-	-	-	-	-	-	-	-	-	ETH_MII_RXD0 ETH_RMII_RXD0	-	-	-	EVENTOUT
	PC5	-	-	-	-	-	-	-	-	-	-	-	ETH_MII_RXD1 ETH_RMII_RXD1	-	-	-	EVENTOUT
	PC6	-	-	TIM3_CH1	TIM8_CH1	-	I2S2_MCK	-	-	USART6_TX	-	-	-	SDIO_D6	DCMI_D0	-	EVENTOUT
	PC7	-	-	TIM3_CH2	TIM8_CH2	-	-	I2S3_MCK	-	USART6_RX	-	-	-	SDIO_D7	DCMI_D1	-	EVENTOUT
	PC8	-	-	TIM3_CH3	TIM8_CH3	-	-	-	-	USART6_CK	-	-	-	SDIO_D0	DCMI_D2	-	EVENTOUT
	PC9	MCO2	-	TIM3_CH4	TIM8_CH4	I2C3_SDA	I2S2_CKIN	I2S3_CKIN	-	-	-	-	-	SDIO_D1	DCMI_D3	-	EVENTOUT
	PC10	-	-	-	-	-	-	SPI3_SCK I2S3_SCK	USART3_TX	UART4_TX	-	-	-	SDIO_D2	DCMI_D8	-	EVENTOUT
	PC11	-	-	-	-	-	-	SPI3_MISO	USART3_RX	UART4_RX	-	-	-	SDIO_D3	DCMI_D4	-	EVENTOUT
	PC12	-	-	-	-	-	-	SPI3_MOSI I2S3_SD	USART3_CK	UART5_TX	-	-	-	SDIO_CK	DCMI_D9	-	EVENTOUT
	PC13	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENTOUT
	PC14- OSC32_IN	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENTOUT
	PC15- OSC32_OUT	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENTOUT



Table 9. Alternate function mapping (continued)

Port		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF014	AF15
		SYS	TIM1/2	TIM3/4/5	TIM8/9/10/11	I2C1/I2C2/I2C3	SPI1/SPI2/I2S2	SPI3/I2S3	USART1/2/3	UART4/5/ USART6	CAN1/CAN2/ TIM12/13/14	OTG_FS/ OTG_HS	ETH	FSMC/SDIO/ OTG_HS	DCMI		
Port F	PF0	-	-	-	-	I2C2_SDA	-	-	-	-	-	-	-	FSMC_A0	-	-	EVENTOUT
	PF1	-	-	-	-	I2C2_SCL	-	-	-	-	-	-	-	FSMC_A1	-	-	EVENTOUT
	PF2	-	-	-	-	I2C2_SMBA	-	-	-	-	-	-	-	FSMC_A2	-	-	EVENTOUT
	PF3	-	-	-	-	-	-	-	-	-	-	-	-	FSMC_A3	-	-	EVENTOUT
	PF4	-	-	-	-	-	-	-	-	-	-	-	-	FSMC_A4	-	-	EVENTOUT
	PF5	-	-	-	-	-	-	-	-	-	-	-	-	FSMC_A5	-	-	EVENTOUT
	PF6	-	-	-	TIM10_CH1	-	-	-	-	-	-	-	-	FSMC_NIORD	-	-	EVENTOUT
	PF7	-	-	-	TIM11_CH1	-	-	-	-	-	-	-	-	FSMC_NREG	-	-	EVENTOUT
	PF8	-	-	-	-	-	-	-	-	-	TIM13_CH1	-	-	FSMC_NIOWR	-	-	EVENTOUT
	PF9	-	-	-	-	-	-	-	-	-	TIM14_CH1	-	-	FSMC_CD	-	-	EVENTOUT
	PF10	-	-	-	-	-	-	-	-	-	-	-	-	FSMC_INTR	-	-	EVENTOUT
	PF11	-	-	-	-	-	-	-	-	-	-	-	-	-	DCMI_D12	-	EVENTOUT
	PF12	-	-	-	-	-	-	-	-	-	-	-	-	FSMC_A6	-	-	EVENTOUT
	PF13	-	-	-	-	-	-	-	-	-	-	-	-	FSMC_A7	-	-	EVENTOUT
	PF14	-	-	-	-	-	-	-	-	-	-	-	-	FSMC_A8	-	-	EVENTOUT
	PF15	-	-	-	-	-	-	-	-	-	-	-	-	FSMC_A9	-	-	EVENTOUT
Port G	PG0	-	-	-	-	-	-	-	-	-	-	-	-	FSMC_A10	-	-	EVENTOUT
	PG1	-	-	-	-	-	-	-	-	-	-	-	-	FSMC_A11	-	-	EVENTOUT
	PG2	-	-	-	-	-	-	-	-	-	-	-	-	FSMC_A12	-	-	EVENTOUT
	PG3	-	-	-	-	-	-	-	-	-	-	-	-	FSMC_A13	-	-	EVENTOUT
	PG4	-	-	-	-	-	-	-	-	-	-	-	-	FSMC_A14	-	-	EVENTOUT
	PG5	-	-	-	-	-	-	-	-	-	-	-	-	FSMC_A15	-	-	EVENTOUT
	PG6	-	-	-	-	-	-	-	-	-	-	-	-	FSMC_INT2	-	-	EVENTOUT
	PG7	-	-	-	-	-	-	-	-	USART6_CK	-	-	-	FSMC_INT3	-	-	EVENTOUT
	PG8	-	-	-	-	-	-	-	-	USART6_RTS	-	-	ETH_PPS_OUT	-	-	-	EVENTOUT
	PG9	-	-	-	-	-	-	-	-	USART6_RX	-	-	-	FSMC_NE2/ FSMC_NCE3	-	-	EVENTOUT
	PG10	-	-	-	-	-	-	-	-	-	-	-	-	FSMC_NCE4_1/ FSMC_NE3	-	-	EVENTOUT
	PG11	-	-	-	-	-	-	-	-	-	-	-	ETH_MII_TX_EN ETH_RMII_TX_EN	FSMC_NCE4_2	-	-	EVENTOUT
	PG12	-	-	-	-	-	-	-	-	USART6_RTS	-	-	-	FSMC_NE4	-	-	EVENTOUT
	PG13	-	-	-	-	-	-	-	-	UART6_CTS	-	-	ETH_MII_TXD0 ETH_RMII_TXD0	FSMC_A24	-	-	EVENTOUT
	PG14	-	-	-	-	-	-	-	-	USART6_TX	-	-	ETH_MII_TXD1 ETH_RMII_TXD1	FSMC_A25	-	-	EVENTOUT
	PG15	-	-	-	-	-	-	-	-	USART6_CTS	-	-	-	-	DCMI_D13	-	EVENTOUT

Table 13. General operating conditions (continued)

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DD}	Standard operating voltage	-	1.8	3.6	V
$V_{DDA}^{(1)}$	Analog operating voltage (ADC limited to 1 M samples)	Must be the same potential as $V_{DD}^{(2)}$	1.8	3.6	
	Analog operating voltage (ADC limited to 2 M samples)		2.4	3.6	
V_{BAT}	Backup operating voltage	-	1.65	3.6	
V_{IN}	Input voltage on RST and FT pins	$2\text{ V} \leq V_{DD} \leq 3.6\text{ V}$	-0.3	5.5	
		$1.7\text{ V} \leq V_{DD} \leq 2\text{ V}$	-0.3	5.2	
	Input voltage on TTa pins	-	-0.3	$V_{DD}+0.3$	
	Input voltage on BOOT0 pin	-	0	9	
V_{CAP1}	Internal core voltage to be supplied externally in REGOFF mode	-	1.1	1.3	
V_{CAP2}					
P_D	Power dissipation at $T_A = 85\text{ °C}$ for suffix 6 or $T_A = 105\text{ °C}$ for suffix 7 ⁽³⁾	LQFP64	-	444	mW
		LQFP100	-	434	
		LQFP144	-	500	
		LQFP176	-	526	
		UFBGA176	-	513	
T_A	Ambient temperature for 6 suffix version	Maximum power dissipation	-40	85	°C
		Low-power dissipation ⁽⁴⁾	-40	105	
	Ambient temperature for 7 suffix version	Maximum power dissipation	-40	105	°C
		Low-power dissipation ⁽⁴⁾	-40	125	
T_J	Junction temperature range	6 suffix version	-40	105	°C
		7 suffix version	-40	125	

1. When the ADC is used, refer to [Table 65: ADC characteristics](#).

2. It is recommended to power V_{DD} and V_{DDA} from the same source. A maximum difference of 300 mV between V_{DD} and V_{DDA} can be tolerated during power-up and power-down operation.

3. If T_A is lower, higher P_D values are allowed as long as T_J does not exceed T_{Jmax} .

4. In low-power dissipation state, T_A can be extended to this range as long as T_J does not exceed T_{Jmax} .

Table 21. Typical and maximum current consumption in Sleep mode

Symbol	Parameter	Conditions	f_{HCLK}	Typ	Max ⁽¹⁾		Unit
				$T_A = 25\text{ °C}$	$T_A = 85\text{ °C}$	$T_A = 105\text{ °C}$	
I_{DD}	Supply current in Sleep mode	External clock ⁽²⁾ , all peripherals enabled ⁽³⁾	120 MHz	38	51	61	mA
			90 MHz	30	43	53	
			60 MHz	20	33	43	
			30 MHz	11	25	35	
			25 MHz	8	21	31	
			16 MHz	6	19	29	
			8 MHz	3.6	17.0	27.0	
			4 MHz	2.4	15.4	25.3	
			2 MHz	1.9	14.9	24.7	
		External clock ⁽²⁾ , all peripherals disabled	120 MHz	8	21	31	
			90 MHz	7	20	30	
			60 MHz	5	18	28	
			30 MHz	3.5	16.0	26.0	
			25 MHz	2.5	16.0	25.0	
			16 MHz	2.1	15.1	25.0	
			8 MHz	1.7	15.0	25.0	
			4 MHz	1.5	14.6	24.6	
			2 MHz	1.4	14.2	24.3	

1. Guaranteed by characterization results, tested in production at V_{DD} max and f_{HCLK} max with peripherals enabled.
2. External clock is 4 MHz and PLL is on when $f_{HCLK} > 25$ MHz.
3. Add an additional power consumption of 1.6 mA per ADC for the analog part. In applications, this consumption occurs only while the ADC is on (ADON bit is set in the ADC_CR2 register).

Figure 25. Typical current consumption vs. temperature in Sleep mode, peripherals ON

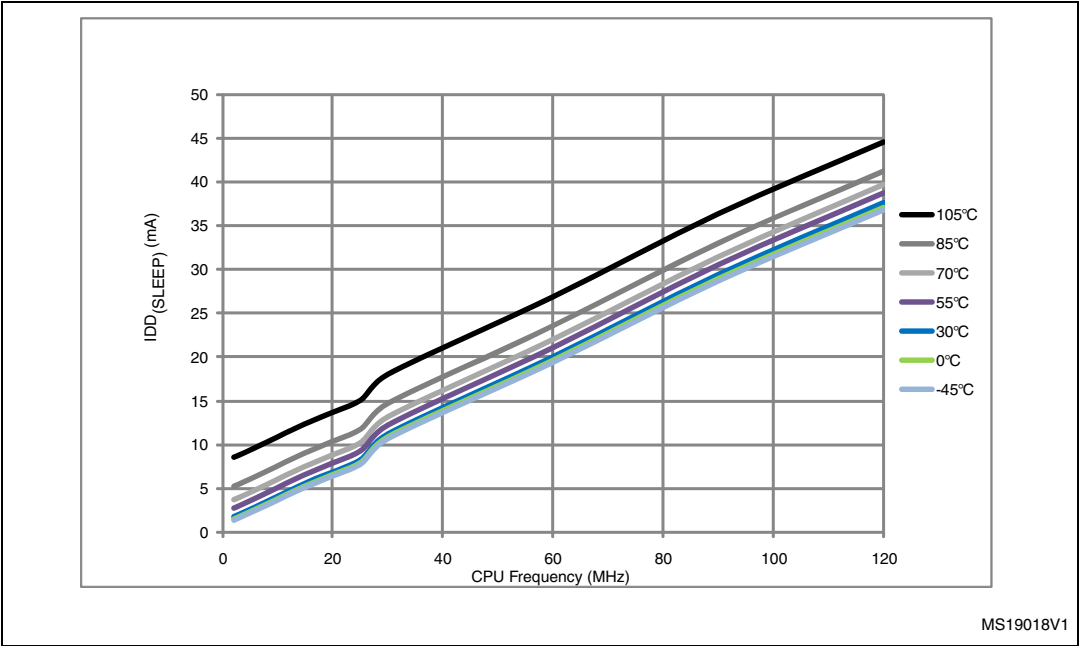


Figure 26. Typical current consumption vs. temperature in Sleep mode, peripherals OFF

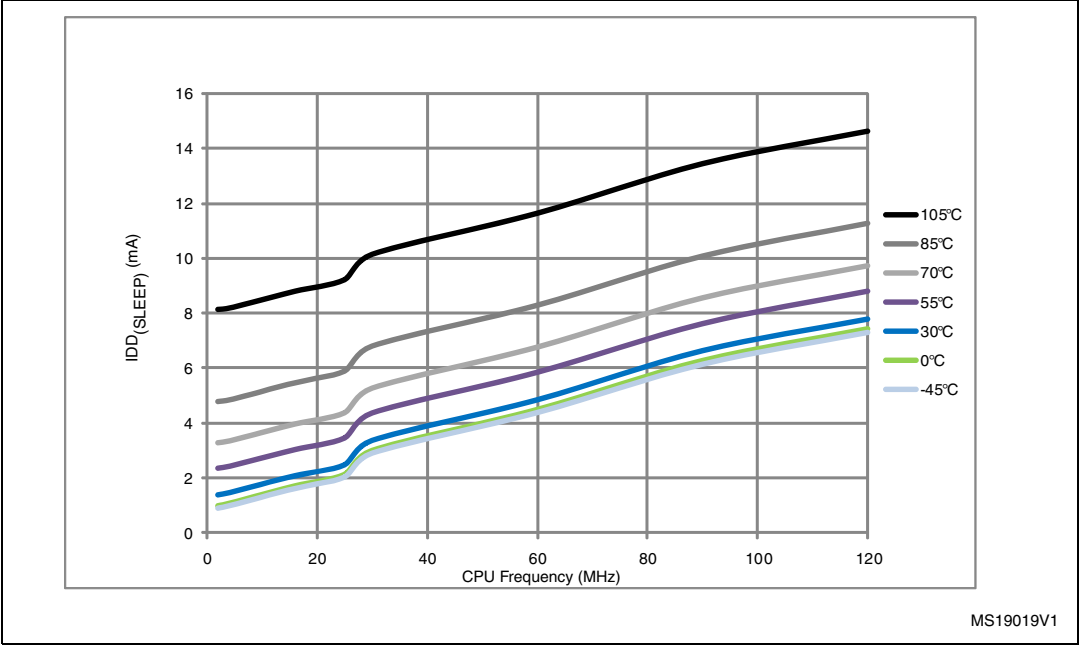
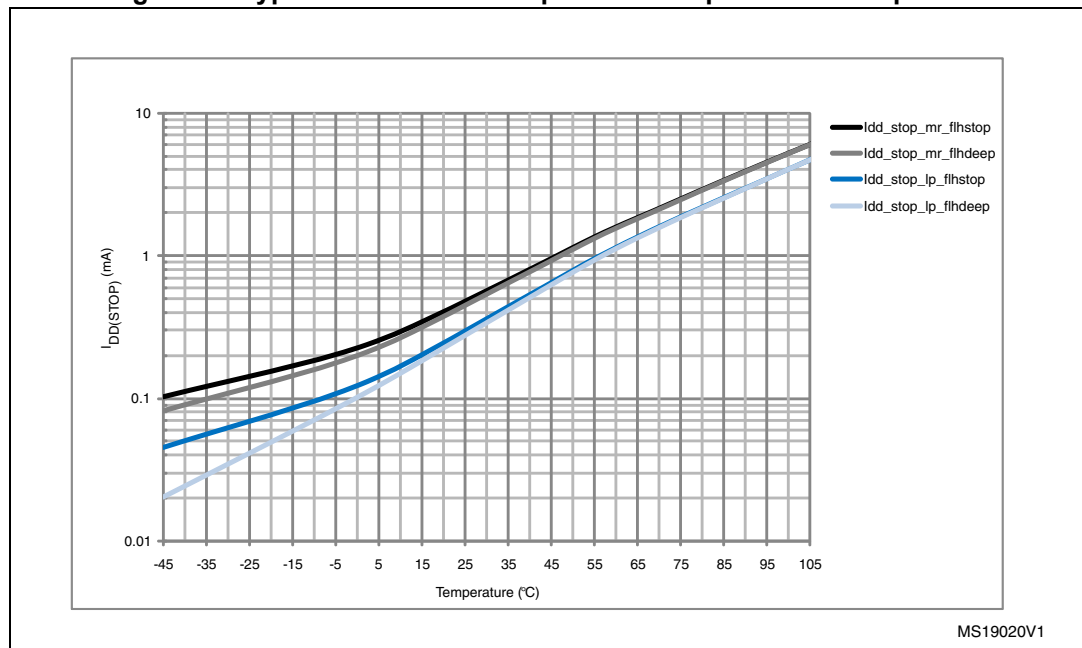


Table 22. Typical and maximum current consumptions in Stop mode

Symbol	Parameter	Conditions	Typ	Max				Unit
			T _A = 25 °C	T _A = 25 °C	T _A = 85 °C	T _A = 105 °C		
I _{DD_STOP}	Supply current in Stop mode with main regulator in Run mode	Flash in Stop mode, low-speed and high-speed internal RC oscillators and high-speed oscillator OFF (no independent watchdog)	0.55	1.2	11.00	20.00	mA	
		Flash in Deep power down mode, low-speed and high-speed internal RC oscillators and high-speed oscillator OFF (no independent watchdog)	0.50	1.2	11.00	20.00		
	Supply current in Stop mode with main regulator in Low-power mode	Flash in Stop mode, low-speed and high-speed internal RC oscillators and high-speed oscillator OFF (no independent watchdog)	0.35	1.1	8.00	15.00		
		Flash in Deep power down mode, low-speed and high-speed internal RC oscillators and high-speed oscillator OFF (no independent watchdog)	0.30	1.1	8.00	15.00		

Figure 27. Typical current consumption vs. temperature in Stop mode



1. All typical and maximum values from table 18 and figure 26 will be reduced over time by up to 50% as part of ST continuous improvement of test procedures. New versions of the datasheet will be released to reflect these changes

Table 23. Typical and maximum current consumptions in Standby mode

Symbol	Parameter	Conditions	Typ			Max ⁽¹⁾		Unit
			T _A = 25 °C			T _A = 85 °C	T _A = 105 °C	
			V _{DD} = 1.8 V	V _{DD} = 2.4 V	V _{DD} = 3.3 V	V _{DD} = 3.6 V		
I _{DD_STBY}	Supply current in Standby mode	Backup SRAM ON, low-speed oscillator and RTC ON	3.0	3.4	4.0	15.1	25.8	μA
		Backup SRAM OFF, low-speed oscillator and RTC ON	2.4	2.7	3.3	12.4	20.5	
		Backup SRAM ON, RTC OFF	2.4	2.6	3.0	12.5	24.8	
		Backup SRAM OFF, RTC OFF	1.7	1.9	2.2	9.8	19.2	

1. Guaranteed by characterization results, not tested in production.

Table 24. Typical and maximum current consumptions in V_{BAT} mode

Symbol	Parameter	Conditions	Typ			Max ⁽¹⁾		Unit
			T _A = 25 °C			T _A = 85 °C	T _A = 105 °C	
			V _{DD} = 1.8 V	V _{DD} = 2.4 V	V _{DD} = 3.3 V	V _{DD} = 3.6 V		
I _{DD_VBAT}	Backup domain supply current	Backup SRAM ON, low-speed oscillator and RTC ON	1.29	1.42	1.68	12	19	μA
		Backup SRAM OFF, low-speed oscillator and RTC ON	0.62	0.73	0.96	8	10	
		Backup SRAM ON, RTC OFF	0.79	0.81	0.86	9	16	
		Backup SRAM OFF, RTC OFF	0.10	0.10	0.10	5	7	

1. Guaranteed by characterization results, not tested in production.

On-chip peripheral current consumption

The current consumption of the on-chip peripherals is given in [Table 25](#). The MCU is placed under the following conditions:

- At startup, all I/O pins are configured as analog inputs by firmware.
- All peripherals are disabled unless otherwise mentioned
- The given value is calculated by measuring the current consumption
 - with all peripherals clocked off
 - with one peripheral clocked on (with only the clock applied)
- The code is running from Flash memory and the Flash memory access time is equal to 3 wait states at 120 MHz
- Prefetch and Cache ON
- When the peripherals are enabled, HCLK = 120MHz, f_{PCLK1} = f_{HCLK}/4, and f_{PCLK2} = f_{HCLK}/2
- The typical values are obtained for V_{DD} = 3.3 V and T_A = 25 °C, unless otherwise specified.

Table 25. Peripheral current consumption (continued)

Peripheral ⁽¹⁾		Typical consumption at 25 °C	Unit
APB1	TIM2	0.61	mA
	TIM3	0.49	
	TIM4	0.54	
	TIM5	0.62	
	TIM6	0.20	
	TIM7	0.20	
	TIM12	0.36	
	TIM13	0.28	
	TIM14	0.25	
	USART2	0.25	
	USART3	0.25	
	UART4	0.25	
	UART5	0.26	
	I2C1	0.25	
	I2C2	0.25	
	I2C3	0.25	
	SPI2	0.20/0.10	
	SPI3	0.18/0.09	
	CAN1	0.31	
	CAN2	0.30	
	DAC channel 1 ⁽²⁾	1.11	
	DAC channel 1 ⁽³⁾	1.11	
	PWR	0.15	
	WWDG	0.15	

Table 29. HSE 4-26 MHz oscillator characteristics^{(1) (2)}

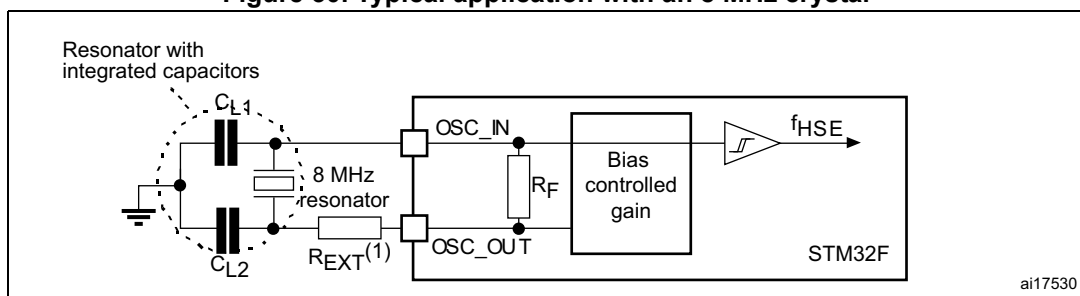
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{OSC_IN}	Oscillator frequency	-	4	-	26	MHz
R_F	Feedback resistor	-	-	200	-	k Ω
I_{DD}	HSE current consumption	$V_{DD}=3.3\text{ V}$, ESR= 30 Ω , $C_L=5\text{ pF@25 MHz}$	-	449	-	μA
		$V_{DD}=3.3\text{ V}$, ESR= 30 Ω , $C_L=10\text{ pF@25 MHz}$	-	532	-	
g_m	Oscillator transconductance	Startup	5	-	-	mA/V
$t_{SU(HSE)}^{(3)}$	Startup time	V_{DD} is stabilized	-	2	-	ms

1. Resonator characteristics given by the crystal/ceramic resonator manufacturer.
2. Guaranteed by characterization results, not tested in production.
3. $t_{SU(HSE)}$ is the startup time measured from the moment it is enabled (by software) to a stabilized 8 MHz oscillation is reached. This value is measured for a standard crystal resonator and it can vary significantly with the crystal manufacturer

For C_{L1} and C_{L2} , it is recommended to use high-quality external ceramic capacitors in the 5 pF to 25 pF range (typ.), designed for high-frequency applications, and selected to match the requirements of the crystal or resonator (see [Figure 30](#)). C_{L1} and C_{L2} are usually the same size. The crystal manufacturer typically specifies a load capacitance which is the series combination of C_{L1} and C_{L2} . PCB and MCU pin capacitance must be included (10 pF can be used as a rough estimate of the combined pin and board capacitance) when sizing C_{L1} and C_{L2} .

Note: For information on electing the crystal, refer to the application note AN2867 "Oscillator design guide for ST microcontrollers" available from the ST website www.st.com.

Figure 30. Typical application with an 8 MHz crystal



1. R_{EXT} value depends on the crystal characteristics.

Low-speed external clock generated from a crystal/ceramic resonator

The low-speed external (LSE) clock can be supplied with a 32.768 kHz crystal/ceramic resonator oscillator. All the information given in this paragraph are based on characterization results obtained with typical external components specified in [Table 30](#). In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

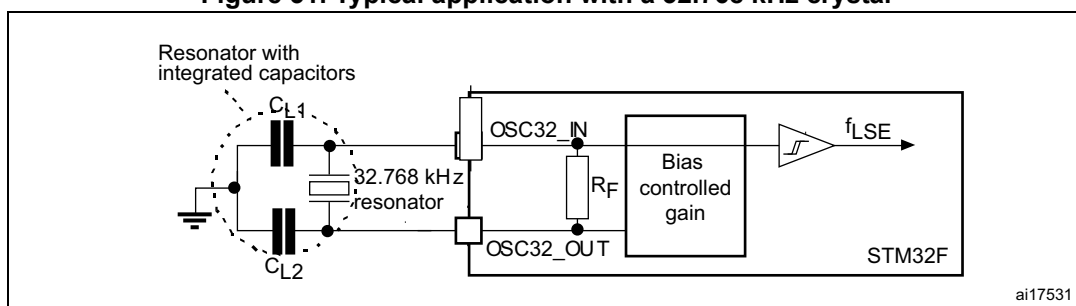
Table 30. LSE oscillator characteristics ($f_{LSE} = 32.768$ kHz) ⁽¹⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
R_F	Feedback resistor	-	-	18.4	-	M Ω
I_{DD}	LSE current consumption	-	-	-	1	μ A
g_m	Oscillator Transconductance	-	2.8	-	-	μ A/V
$t_{SU(LSE)}$ ⁽²⁾	startup time	V_{DD} is stabilized	-	2	-	s

1. Guaranteed by design, not tested in production.

2. $t_{SU(LSE)}$ is the startup time measured from the moment it is enabled (by software) to a stabilized 32.768 kHz oscillation is reached. This value is measured for a standard crystal resonator and it can vary significantly with the crystal manufacturer

Note: For information on electing the crystal, refer to the application note AN2867 "Oscillator design guide for ST microcontrollers" available from the ST website www.st.com.

Figure 31. Typical application with a 32.768 kHz crystal

6.3.9 Internal clock source characteristics

The parameters given in [Table 31](#) and [Table 32](#) are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in [Table 13](#).

High-speed internal (HSI) RC oscillator

Table 31. HSI oscillator characteristics ⁽¹⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{HSI}	Frequency	-	-	16	-	MHz
ACC_{HSI}	HSI user-trimming step ⁽²⁾	-	-	-	1	%
	Accuracy of the HSI oscillator	$T_A = -40$ to 105 °C ⁽³⁾	- 8	-	4.5	%
		$T_A = -10$ to 85 °C ⁽³⁾	- 4	-	4	%
		$T_A = 25$ °C ⁽⁴⁾	- 1	-	1	%
$t_{su(HSI)}$ ⁽²⁾	HSI oscillator startup time	-	-	2.2	4.0	μ s
$I_{DD(HSI)}$ ⁽²⁾	HSI oscillator power consumption	-	-	60	80	μ A

1. $V_{DD} = 3.3$ V, $T_A = -40$ to 105 °C unless otherwise specified.

2. Guaranteed by design, not tested in production.

3. Guaranteed by characterization results.

4. Factory calibrated, parts not soldered.

6.3.16 I/O port characteristics

General input/output characteristics

Unless otherwise specified, the parameters given in [Table 49](#) are derived from tests performed under the conditions summarized in [Table 13: General operating conditions](#).

All I/Os are CMOS and TTL compliant.

Table 45. I/O static characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V _{IL}	FT, TTa and NRST I/O input low level voltage	1.7 V≤V _{DD} ≤3.6 V	-	-	0.35V _{DD} −0.04 ⁽¹⁾	V
					0.3V _{DD} ⁽²⁾	
	BOOT0 I/O input low level voltage	1.75 V≤V _{DD} ≤3.6 V, −40 °C≤T _A ≤105 °C	-	-	0.1V _{DD} +0.1 ⁽¹⁾	
1.7 V≤V _{DD} ≤3.6 V, 0 °C≤T _A ≤105 °C		-	-			
V _{IH}	FT, TTa and NRST I/O input high level voltage ⁽⁵⁾	1.7 V≤V _{DD} ≤3.6 V	0.45V _{DD} +0.3 ⁽¹⁾	-	-	V
			0.7V _{DD} ⁽²⁾			
	BOOT0 I/O input high level voltage	1.75 V≤V _{DD} ≤3.6 V, −40 °C≤T _A ≤105 °C	0.17V _{DD} +0.7 ⁽¹⁾	-	-	
		1.7 V≤V _{DD} ≤3.6 V, 0 °C≤T _A ≤105 °C				
V _{HYS}	FT, TTa and NRST I/O input hysteresis	1.7 V≤V _{DD} ≤3.6 V	0.45V _{DD} +0.3 ⁽¹⁾	-	-	V
	BOOT0 I/O input hysteresis	1.75 V≤V _{DD} ≤3.6 V, −40 °C≤T _A ≤105 °C	10%V _{DDIO} ⁽¹⁾⁽³⁾	-	-	
			1.7 V≤V _{DD} ≤3.6 V, 0 °C≤T _A ≤105 °C	100 ⁽¹⁾	-	
I _{lkg}	I/O input leakage current ⁽⁴⁾	V _{SS} ≤V _{IN} ≤V _{DD}	-	-	±1	μA
	I/O FT input leakage current ⁽⁵⁾	V _{IN} = 5 V	-	-	3	

Figure 42. SPI timing diagram - master mode

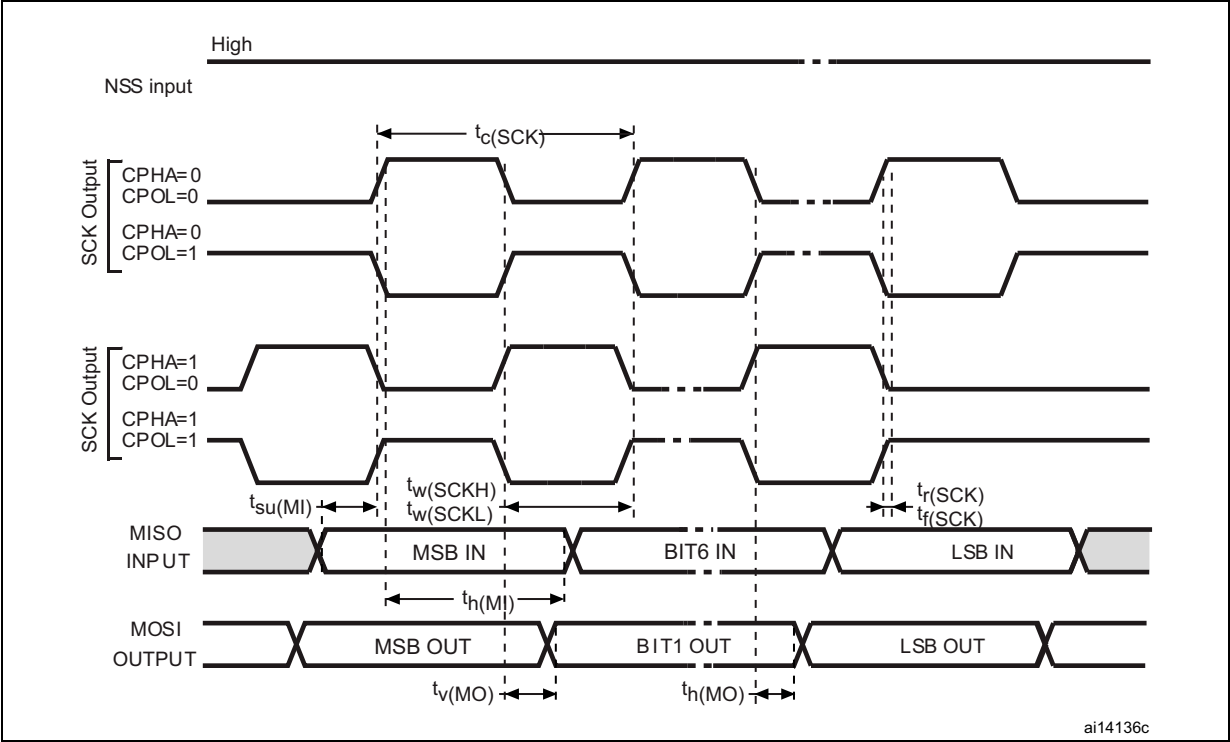


Table 54. I²S characteristics

Symbol	Parameter	Conditions	Min	Max	Unit
f_{CK} $1/t_{c(CK)}$	I ² S clock frequency	Master, 16-bit data, audio frequency = 48 kHz, main clock disabled	1.23	1.24	MHz
		Slave	0	$64F_S^{(1)}$	
$t_{r(CK)}$ $t_{f(CK)}$	I ² S clock rise and fall time	Capacitive load $C_L = 50$ pF	-	(2)	ns
$t_{V(WS)}^{(3)}$	WS valid time	Master	0.3	-	
$t_{H(WS)}^{(3)}$	WS hold time	Master	0	-	
$t_{su(WS)}^{(3)}$	WS setup time	Slave	3	-	
$t_{H(WS)}^{(3)}$	WS hold time	Slave	0	-	
$t_{w(CKH)}^{(3)}$ $t_{w(CKL)}^{(3)}$	CK high and low time	Master $f_{PCLK} = 30$ MHz	396	-	
$t_{su(SD_MR)}^{(3)}$ $t_{su(SD_SR)}^{(3)}$	Data input setup time	Master receiver Slave receiver	45 0	-	
$t_{H(SD_MR)}^{(3)(4)}$ $t_{H(SD_SR)}^{(3)(4)}$	Data input hold time	Master receiver: $f_{PCLK} = 30$ MHz, Slave receiver: $f_{PCLK} = 30$ MHz	13 0	-	
$t_{V(SD_ST)}^{(3)(4)}$	Data output valid time	Slave transmitter (after enable edge)	-	30	
$t_{H(SD_ST)}^{(3)}$	Data output hold time	Slave transmitter (after enable edge)	10	-	
$t_{V(SD_MT)}^{(3)(4)}$	Data output valid time	Master transmitter (after enable edge)	-	6	
$t_{H(SD_MT)}^{(3)}$	Data output hold time	Master transmitter (after enable edge)	0	-	

1. F_S is the sampling frequency. Refer to the I2S section of the STM32F20xxx/21xxx reference manual for more details. f_{CK} values reflect only the digital peripheral behavior which leads to a minimum of $(I2SDIV/(2 \cdot I2SDIV + ODD))$, a maximum of $(I2SDIV + ODD)/(2 \cdot I2SDIV + ODD)$ and F_S maximum values for each mode/condition.

2. Refer to [Table 47: I/O AC characteristics](#).

3. Guaranteed by design, not tested in production.

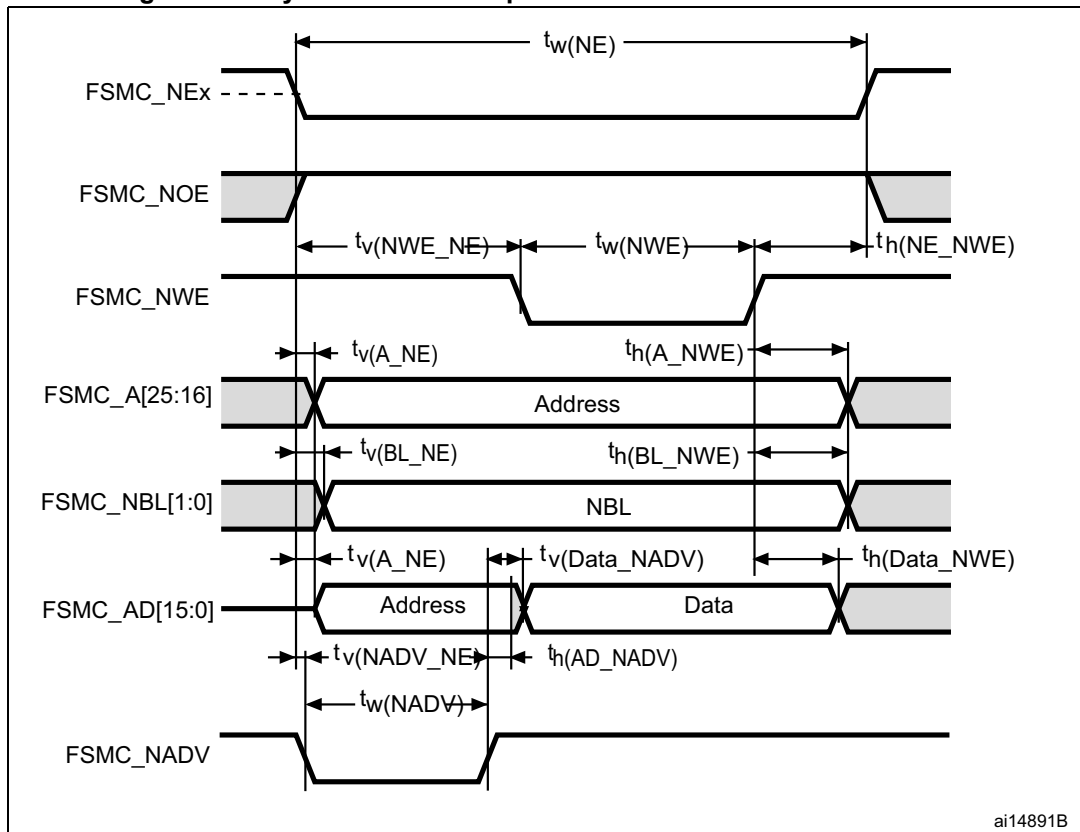
4. Depends on f_{PCLK} . For example, if $f_{PCLK} = 8$ MHz, then $T_{PCLK} = 1/f_{PCLK} = 125$ ns.

Table 73. Asynchronous multiplexed PSRAM/NOR read timings⁽¹⁾⁽²⁾ (continued)

Symbol	Parameter	Min	Max	Unit
$t_{h(Data_NE)}$	Data hold time after FSMC_NEx high	0	-	ns
$t_{h(Data_NOE)}$	Data hold time after FSMC_NOE high	0	-	ns

1. $C_L = 30$ pF.

2. Guaranteed by characterization results, not tested in production.

Figure 58. Asynchronous multiplexed PSRAM/NOR write waveforms

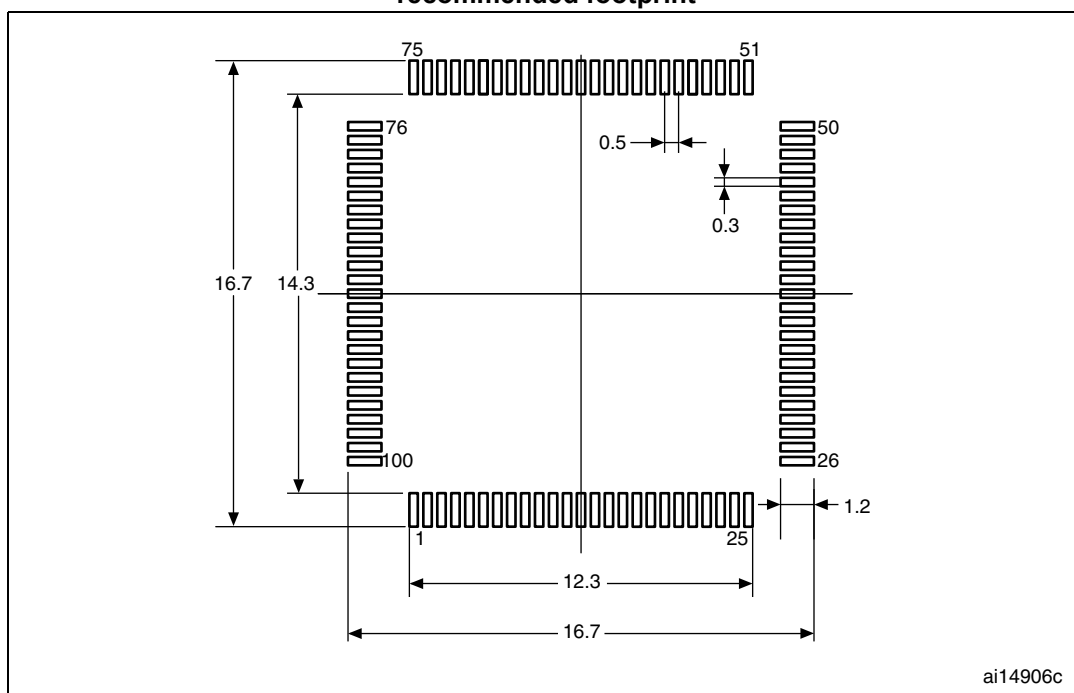
ai14891B

Table 74. Asynchronous multiplexed PSRAM/NOR write timings⁽¹⁾⁽²⁾

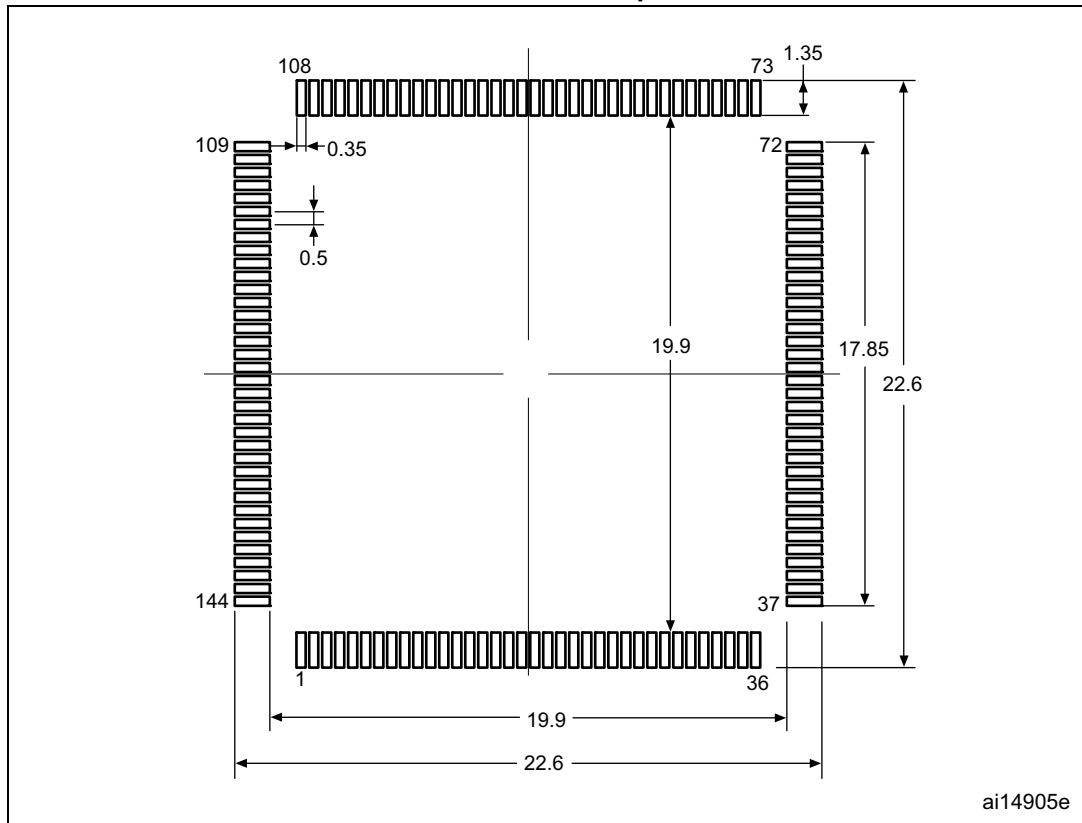
Symbol	Parameter	Min	Max	Unit
$t_{w(NE)}$	FSMC_NE low time	$4T_{HCLK}-1$	$4T_{HCLK}+1$	ns
$t_{v(NWE_NE)}$	FSMC_NEx low to FSMC_NWE low	$T_{HCLK}-1$	T_{HCLK}	ns
$t_{w(NWE)}$	FSMC_NWE low time	$2T_{HCLK}$	$2T_{HCLK}+1$	ns
$t_{h(NE_NWE)}$	FSMC_NWE high to FSMC_NE high hold time	$T_{HCLK}-1$	-	ns
$t_{v(A_NE)}$	FSMC_NEx low to FSMC_A valid	-	0	ns
$t_{v(NADV_NE)}$	FSMC_NEx low to FSMC_NADV low	1	2	ns
$t_{w(NADV)}$	FSMC_NADV low time	$T_{HCLK}-2$	$T_{HCLK}+2$	ns
$t_{h(AD_NADV)}$	FSMC_AD(address) valid hold time after FSMC_NADV high	T_{HCLK}	-	ns

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
D3	-	12.000	-	-	0.4724	-
E	15.800	16.000	16.200	0.6220	0.6299	0.6378
E1	13.800	14.000	14.200	0.5433	0.5512	0.5591
E3	-	12.000	-	-	0.4724	-
e	-	0.500	-	-	0.0197	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0.0°	3.5°	7.0°	0.0°	3.5°	7.0°
ccc	-	-	0.080	-	-	0.0031

Figure 78. LQFP100 - 100-pin, 14 x 14 mm low-profile quad flat recommended footprint



**Figure 81. LQFP144 - 144-pin, 20 x 20 mm low-profile quad flat package
recommended footprint**



1. Dimensions are expressed in millimeters.